



SPECIFICATION

LCGT Power Recycling Mirror 2 (PR2)

Table with columns: AUTHOR, CHECKED, DATE, APPROVALS (DCN NO., REV, DATE). Row 1: Eiichi Hirose, Nov21-11, V1, Nov21-11.

Applicable Documents

- LCGT-MIR-D00005-V1 Fused Silica Substrate, LCGT PR2
LCGT-XXXXX-A Fused Silica Blank, PR2
LCGT-XXXXX-A Fused Silica Blank, PR2

Requirements

Physical Configuration

According to LCGT-MIR-D00005-V1 Fused Silica Substrate, LCGT PR2

Fabricate from

- LCGT-XXXXX- A Fused Silica Blank, PR2
LCGT-XXXXX- A Fused Silica Blank, PR2

Registration Marks

Registration marks shall be etched, ground or sandblasted and located per LCGT-MIR-D00005-V1

Side and Bevel Polish

All surfaces, including Sides and Bevels shall be polished using a progression of smaller grit sizes. The last step before final polish shall be equal to or less than a five micrometer grit finish. These surfaces shall appear transparent with no grey, scuffs or scratches visible to the naked eye when viewed in normal room light against a black background.

Bevel

Bevel for safety per LCGT-MIR-D00005-V1

Serial Number

Serial Number "PR2 YY" shall be etched, ground or sandblasted on the barrel of the optic per LCGT-MIR-D00005-V1, where Y is incremental starting with 01.

Witness Samples:

Vendor will deliver two 2-inch witness samples according to requirements on page 4 of this specification



## LCGT Power Recycling Mirror 2 (PR2)

### Scratches, Sleeks and Point defects

Point defects of radius greater than 25 micrometers are treated like scratches for the purpose of this specification.

#### Scratches and Sleeks, Surface 1

There shall be no scratches and sleeks within the central 15mm diameter.

The total area of scratches and sleeks within the central 40 mm diameter shall not exceed 800 square micrometers (width times length.)

The total area of scratches and sleeks outside the central 40 mm diameter shall not exceed  $22 \times 10^4$  square micrometers (width times length.)

#### Point Defects, Surface 1

There shall be no point defects of radius greater than  $2 \mu\text{m}$  within the central 15 mm diameter.

There shall be no more than 2 point defects of radius greater than  $2 \mu\text{m}$  within the central 40mm diameter.

Average density of defects less than  $2 \mu\text{m}$  radius within the central 40mm diameter shall be no more than or equal to 1 per  $4\text{mm}^2$

The maximum concentration of localized defects over the central 40mm diameter shall be no more than 30 square micrometers per 1mm diameter

#### Scratch and Point Defect Inspection Method

1. The surface is examined visually by two observers independently. The examination is done against a dark background using a fiber optic illumination system of at least 200 W total power. A 100% inspection of the surface is carried out. Pits and scratches down to 2 micrometers in width can be detected using this method of inspection. Any scratches or sleeks that are detected will be measured using a calibrated eyepiece.

2. Further inspection will be done with a minimum 6X eyeglass using the same illumination conditions, again with two observers. Sleeks down to 0.5 micrometers wide can be detected using this method. The surface will be scanned along one or two chords from centre to edge, then at ten positions around the edge, and ten to fifteen positions near the centre.

3. An inspection is then carried out with a dark or bright field microscope, with 5x objective at four positions at each of the following locations:

- a) Within 5mm of the center of the surface.
- b) Equally spaced along the circumference of a centered, 15 mm diameter circle.

**LCGT Power Recycling Mirror 2 (PR2)****Optical Surface Figure, measured over the central 40 mm diameter**

**Surface 1:** Spherical, convex. Radius of curvature: 2.763 m -0.010m, +0.010 m absolute accuracy  
Astigmatism: < 8 nm Amplitude of the Zernike coefficient  $Z_{2,2}$  as defined in Born and Wolf pp. 523-525.

**Surface 2:** Nominally flat. ROC > |7000m|

**Surface Error, Low Spatial Frequency: measurement aperture to 1 mm<sup>-1</sup>**

The following root mean square standard deviation ( $\sigma_{\text{rms}}$ ) values are calculated from the phase maps which are to be provided with each optic. For this calculation the amplitudes for the best fit Zernike terms  $Z_{0,0}$ ,  $Z_{1,1}$ ,  $Z_{2,0}$  and  $Z_{2,2}$  or corresponding Seidel aberrations are subtracted from the phase map. Known bad pixels may be excluded from this calculation.

Surface 1, Frequency Band: < 1 mm<sup>-1</sup>  
Measured outside the central 20 mm diameter aperture:  $\sigma_{\text{rms}} < 0.5$  nanometers  
Measured over the central 40 mm diameter aperture:  $\sigma_{\text{rms}} < 1.0$  nanometers

Surface 2, Frequency Band: < 1 mm<sup>-1</sup>  
Measured outside the central 60 mm diameter aperture:  $\sigma_{\text{rms}} < 40$  nanometers

**Error, High Spatial Frequency: 1– 750 mm<sup>-1</sup>**

Surface 1 HSF error  $\sigma_{\text{rms}} \leq 0.3$  nanometers

Measured at the following locations:

1. Within 2mm of the center of the surface.
2. Four positions equally spaced along the circumference of a centered, 10 mm diameter circle.
3. Three positions equally spaced along the circumference of a centered, 20 mm diameter circle.

Surface 2 HSF error  $\sigma_{\text{rms}} \leq 0.4$  nanometers

Measured at the center of the surface

**LCGT Power Recycling Mirror 2 (PR2)****Inspection****Table 1: Inspections**

Specification	Test Method and frequency	Data Delivered
Dimensions	Measurement 100%	Measurement Results
Scratches and Point defects methods 1 and 2	Visual Inspection 100%	Hand sketch including scratch/pit dimensions
Scratches and Point defects method 3	Visual Inspection 100%	Digital image of each inspection location
Figure	Interferometry 100%	Surface phase maps
Errors - Low Spatial Frequency	Interferometry 100%	Surface phase maps
Errors - High Spatial Frequency	Interferometry 100%	Surface maps for 3 central locations. Numerical values included with certification

Orientation: For the purpose of full surface phase maps the data shall be oriented such that the substrate registration mark is at the top center of the data.

Format: All Data shall be delivered according to Table 1. In addition to the hard copy, an electronic data set of the phase maps shall be delivered in ASCII format.